Search Notes										

Application/Control No.	Applicant(s)/Patent under Reexamination
10/588,262	NAUER, MARCEL
Examiner	Art Unit
Hongmin Fan	2612

SEARCHED					
Class	Subclass	Date	Examiner		
340	572.1	2/1/2008	HF		
-	572.5				
	572.7				
343	700				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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	<u>.</u> .	<u> </u>			

SEARCH NO (INCLUDING SEARCH	TES I STRATEGY)
	DATE	EXMR
D. Goins	2/1/2008	HF
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